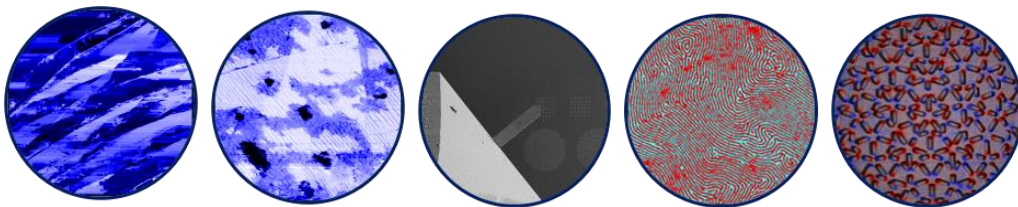


A new way for in-situ correlative analysis of magnetic and conductive nanostructures by combination of AFM & SEM

September 18th, 2020

16.00 - 17.30

Faculty of Civil and Industrial Engineering - Sapienza University of Rome



ABSTRACT

The combination of different analytical methods into one instrument is of great importance for the simultaneous acquisition of complementary information. Especially highly localized probing of mechanical, electrical, magnetic, chemical and crystallographic properties on the nanoscale represents a key success factor for gaining new insights in the micro and nano world. Here, we present a unique AFM – the AFSEM nano – designed for seamless integration into scanning electron microscopes (SEM) or dual beam systems. It allows direct in-situ combination of these complementary techniques due to the simultaneous operation of SEM and AFM inside the vacuum chamber. We will highlight the advantages of correlative in-situ analysis by showing exciting results for variety of different magnetic and conductive nanostructures.

Note: A link to the recording of this event will be provided to all registrants, even if they are unable to attend at the time of broadcast.

SPEAKER:

Dr. Pinar Frank – Head of Applications, GETec Microscopy

<https://www.getec-afm.com/>